# MSKSEMI 美森科













**ESD** 

TV/S

TSS

MOV

GDI

PIFD

BSS84LT1G-MS

**Product specification** 





## **General Features**

- -55 V,-0.3A, RDS(ON) =4.0Ω@VGS = 10V
- Improved dv/dt capability
- Fast switching
- Green Device Available
- ESD protected up to 2KV

# **Application**

- Notebook
- Load Switch
- Battery Protection

## **Reference News**

PACKAGE OUTLINE	Pin Configuration	Marking
SOT-23	Go	PD*



## Absolute Maximum Ratings (TA=25℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
Vos	Drain-Source Voltage	-55	V
Vgs	Gate-Source Voltage	±20	V
lb	Drain Current – Continuous (T <sub>A</sub> =25°C)	-0.3	Α
	Drain Current – Continuous (T <sub>A</sub> =70°C)	-0.2	Α
Ірм	Drain Current – Pulsed <sup>1</sup>	-1.2	А
PD	Power Dissipation (T <sub>A</sub> =25°C)	1.0	W
	Power Dissipation – Derate above 25°C	12.5	mW/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
RθJA	Thermal Resistance Junction to ambient		80	°C/W

## Electrical Characteristics (TJ=25 $^{\circ}$ C , unless otherwise noted)

### Off Characteristics

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-55			V
lpss	Drain-Source Leakage Current	V <sub>DS</sub> =-55V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			- 1	uA
1055	Brain-Source Learlage Outrette	V <sub>DS</sub> =-48V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			- 10	uA
lgss	Gate-Source Leakage Current	Vgs= ±20V , Vps=0V			±20	uA

### On Characteristics

RDS(ON) Static Drain-Source On-Resistance		Vgs=-10V , Ip=-0.3A		4.0	5	Ω
Table Drain Course on Resistance	Vgs=-4.5V , ID=-0.2A		3.5	6.0	1	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA	-1.0	- 1.7	-2.5	V
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-0.3A		0.4		S



## Dynamic and switching Characteristics

Qg	Total Gate Charge <sup>2, 3</sup>			2.8	
Qgs	Gate-Source Charge <sup>2, 3</sup>	V <sub>DS</sub> =-30V , V <sub>GS</sub> =-10V , I <sub>D</sub> =-0.3A		0.96	 nC
Qgd	Gate-Drain Charge <sup>2,3</sup>			0.6	
Td(on)	Turn-On Delay Time <sup>2, 3</sup>			3	
Tr	Rise Time <sup>2, 3</sup>	V <sub>DD</sub> =-30V , V <sub>GS</sub> =-10V , R <sub>G</sub> =6Ω		5	 
Td(off)	Turn-Off Delay Time <sup>2,3</sup>	ID=-0.3A		14	 ns
Tf	Fall Time <sup>2,3</sup>			9	
Ciss	Input Capacitance			30.5	
Coss	Output Capacitance	V <sub>DS</sub> =-30V , V <sub>GS</sub> =0V , F=1MHz		15.1	 pF
Crss	Reverse Transfer Capacitance			7	

## **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-0.3	Α
Іѕм	Pulsed Source Current	VG-VD-OV , FOICE Culteril			-0.6	Α
Vsp	Diode Forward Voltage V <sub>GS</sub> =0V , I <sub>S</sub> =-0.2A , T <sub>J</sub> =25°C				-1.2	V
Trr	Reverse Recovery Time VR=-50V, IS=-0.3A			13.5		nS
Qrr	Reverse Recovery Charge	di/dt=100A/ps, TJ=25C		3		nC

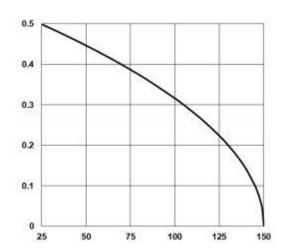
#### Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- 3. Essentially independent of operating temperature.



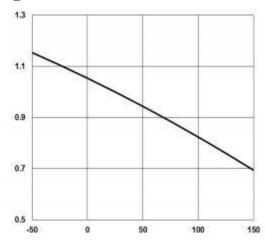
-ID , Continuous Drain Current (A)

Normalized Gate Threshold Voltage



 $T_J$  , Junction Temperature (°C)

Fig.1 Continuous Drain Current vs. Tc



T<sub>J</sub> , Junction Temperature (°C)

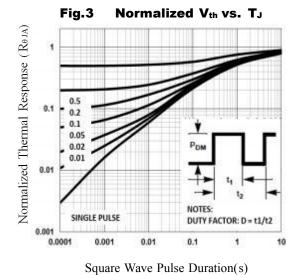
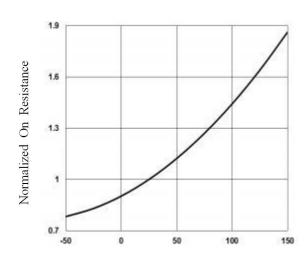


Fig. 5 Normalized Transient Impedance



T<sub>J</sub> , Junction Temperature (°C)

Fig. 2 Normalized RDSON vs. TJ

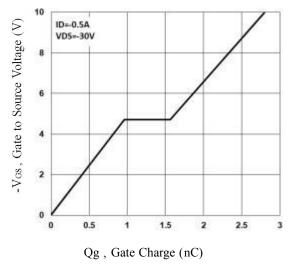
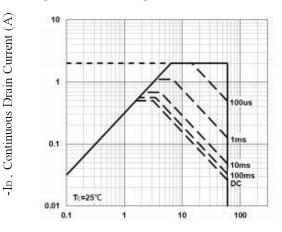


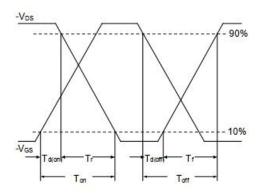
Fig.4 Gate Charge Waveform



-VDS,Drain to Source Voltage (V)

Fig.6 Maximum Safe Operation Area





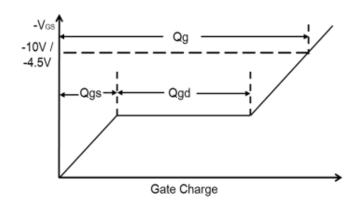


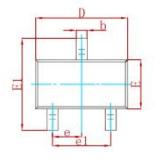
Fig. 7 Switching Time Waveform

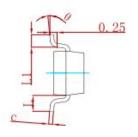
Fig. 8 Gate Charge Waveform

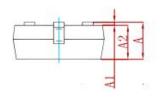




## PACKAGE MECHANICAL DATA

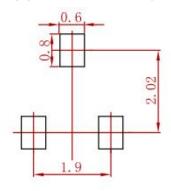






Cumbal	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950 TYP		0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550	REF	0.022	REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

# **Suggested Pad Layout**



## Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
BSS84LT1G-MS	SOT-23	3000



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